


<b>Search Notes</b>  	<b>Application/Control No.</b>  10661534	<b>Applicant(s)/Patent Under Reexamination</b>  KATAYAMA ET AL.
	<b>Examiner</b>  DEVONA E FAULK	<b>Art Unit</b>  2615

SEARCHED			
Class	Subclass	Date	Examiner
381	105,104,106,102	3/29/07	DEF
381	311,105,104,311	9/29/07	DEF
455	41.2,420,430	4/11/08	DEF

SEARCH NOTES		
Search Notes	Date	Examiner
Assignee/Inventor Search	3/29/07	DEF
combined class/word search 381/102-109	3/29,31/07	DEF
Additional search	9/29/07	DEF
Reviewed applicant's arguments; maintained rejection	4/11/08	DEF
Additional search	4/11/08	DEF
Consulted with Nghi Han Ly of class 455, suggested 455/41.2,420 and 430	4/11/08	DEF

INTERFERENCE SEARCH			
Class	Subclass	Date	Examiner